

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of: Kang-Deog SUH, et al.

Serial No.: 10/712,652

Examiner: Nguyen, Tan

Filed: November 12, 2003

Group Art Unit: 2827

Confirmation No.: 8964

For: FLASH MEMORY DEVICE AND PROGRAM VERIFICATION METHOD  
THEREOF

Mail Stop Issue Fee  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**APPLICANT'S COMMENTS ON EXAMINER'S STATEMENT OF REASONS FOR  
ALLOWANCE**

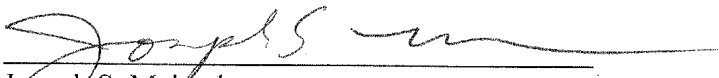
Responsive to the Notice of Allowance mailed April 21, 2006, Applicant has the following comments on the statement of reasons for allowance:

The elements recited in the Examiner's reasons for allowance are not necessarily required in each claim specified. For example, the Examiner states that the prior art fails to disclose a detailed structure of a program verification voltage generator in combination with a word line level selector as in claims 1, 3-4, 11, 13-16 and 24-25. However, not every claim listed recites the detailed structure.

**Customer No. 20575**

Respectfully submitted,

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